

<b>Notice of References Cited</b>	Application/Control No. 09/638,491	Applicant(s)/Patent Under Reexamination FELDMAN, MICHAEL	
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Template Software, Developing a WFT Workflow System, Whole manual, 1997 copyright 1998.
	V	Template Software, Using the WFT Development Environment, Whole manual, 1997 copyright 1998.
	W	Template Software, Using the SNAP Communication Component, Whole manual, 1997 copyright 1998.
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